


<b>Search Notes</b>  	<b>Application/Control No.</b>  10750606	<b>Applicant(s)/Patent Under Reexamination</b>  BOUCHIER ET AL.
	<b>Examiner</b>  RAYMOND PHAN	<b>Art Unit</b>  2111

SEARCHED			
Class	Subclass	Date	Examiner
710	300-313,315-317,8-19	3/1/08	RP
709	201-203	3/1/08	RP
709	217-222	3/1/08	RP

SEARCH NOTES			
Search Notes		Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
710	311-312,301-302	3/7/08	RP